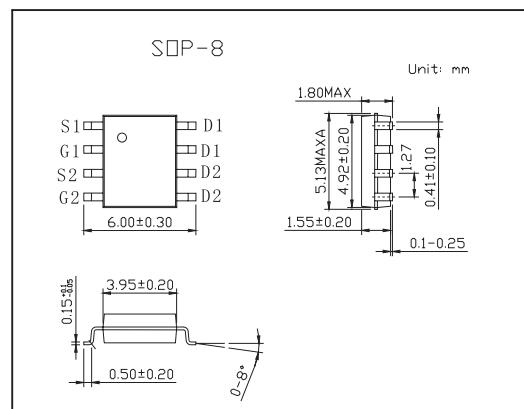
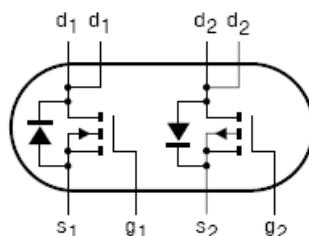


# KHC2300

## ■ Features

- High-speed switching
- No secondary breakdown.



## ■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	N-Channel	P-Channel	Unit	
Drain to Source Voltage	V <sub>DSS</sub>	300	-300	V	
Gate to Source Voltage	V <sub>GS</sub>	±20	±20	V	
Drain Current Ts = 80°C *1	I <sub>D</sub>	340	-235	A	
peak drain current *2	I <sub>DM</sub>	14	-0.9	A	
total power dissipation Ts = 80°C; *3	P <sub>tot</sub>	1.6	W		
T <sub>amb</sub> = 25 °C; *4		1.8			
T <sub>amb</sub> = 25°C; *5		0.9			
T <sub>amb</sub> = 25 °C; *6		1.2			
storage temperature	T <sub>stg</sub>	-55 to 150		°C	
operating junction temperature	T <sub>j</sub>	-55 to 150		°C	
thermal resistance from junction to soldering point	R <sub>th j-s</sub>	43		K/W	

\*1. Ts is the temperature at the soldering point of the drain leads.

\*2. Pulse width and duty cycle limited by maximum junction temperature.

\*3. Maximum permissible dissipation per MOS transistor. (So both devices may be loaded up to 1.6 W at the same time).

\*4. Maximum permissible dissipation per MOS transistor. Value based on a printed-circuit board with an R<sub>th a-tp</sub> (ambient to tie-point) of 27.5 K/W.

\*5. Maximum permissible dissipation per MOS transistor. Value based on a printed-circuit board with an R<sub>th a-tp</sub> (ambient to tie-point) of 90 K/W.

\*6. Maximum permissible dissipation if only one MOS transistor dissipates. Value based on a printed-circuit board with an R<sub>th a-tp</sub> (ambient to tie-point) of 90 K/W.

**KHC2300**

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Type	Min	Typ	Max	Unit
drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0; I <sub>D</sub> = 10 µA	N-Ch	300			V
		V <sub>GS</sub> = 0; I <sub>D</sub> = -10 µA	P-Ch	-300			V
gate-source threshold voltage	V <sub>Gsth</sub>	V <sub>GS</sub> = V <sub>DS</sub> ; I <sub>D</sub> = 1 mA	N-Ch	0.8		2	V
		V <sub>GS</sub> = V <sub>DS</sub> ; I <sub>D</sub> = -1 mA	P-Ch	-0.8		-2	V
drain-source leakage current	I <sub>DSS</sub>	V <sub>GS</sub> = 0; V <sub>DS</sub> = 240 V	N-Ch			100	nA
		V <sub>GS</sub> = 0; V <sub>DS</sub> = -240 V	P-Ch			-100	nA
gate leakage current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20 V; V <sub>DS</sub> = 0	N-Ch			±100	nA
			P-Ch			±100	nA
drain-source on-state resistance	R <sub>DSON</sub>	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 170m A	N-Ch			8	Ω
		V <sub>GS</sub> = -10 V; I <sub>D</sub> = -115m A	P-Ch			17	Ω
input capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0; V <sub>DS</sub> = 50 V; f = 1 MHz	N-Ch		57		pF
		V <sub>GS</sub> = 0; V <sub>DS</sub> = -50 V; f = 1 MHz	P-Ch		45		pF
output capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0; V <sub>DS</sub> = 50 V; f = 1 MHz	N-Ch		15		pF
		V <sub>GS</sub> = 0; V <sub>DS</sub> = -50 V; f = 1 MHz	P-Ch		15		pF
reverse transfer capacitance	C <sub>rss</sub>	V <sub>GS</sub> = 0; V <sub>DS</sub> = 50 V; f = 1 MHz	N-Ch		2.6		pF
		V <sub>GS</sub> = 0; V <sub>DS</sub> = -50 V; f = 1 MHz	P-Ch		3		pF
total gate charge	Q <sub>G</sub>	V <sub>GS</sub> = 10 V; V <sub>DS</sub> = 50 V; I <sub>D</sub> = 170m A	N-Ch		2097		nC
		V <sub>GS</sub> = 10 V; V <sub>DS</sub> = -50 V; I <sub>D</sub> = -115m A	P-Ch		2137		nC
gate-source charge	Q <sub>GS</sub>	V <sub>GS</sub> = 10 V; V <sub>DS</sub> = 50 V; I <sub>D</sub> = 170m A	N-Ch		75		nC
		V <sub>GS</sub> = -10 V; V <sub>DS</sub> = -50 V; I <sub>D</sub> = -115m A	P-Ch		68		nC
gate-drain charge	Q <sub>GD</sub>	V <sub>GS</sub> = 10 V; V <sub>DS</sub> = 50 V; I <sub>D</sub> = 170m A	N-Ch		527		nC
		V <sub>GS</sub> = -10 V; V <sub>DS</sub> = -50 V; I <sub>D</sub> = -115m A	P-Ch		674		nC
turn-on time	t <sub>on</sub>	V <sub>GS</sub> = 0 to 10 V; V <sub>DD</sub> = 50V; I <sub>D</sub> = 170mA	N-Ch		2.5	10	ns
		V <sub>GS</sub> = 0 to -10 V; V <sub>DD</sub> = -50 V; I <sub>D</sub> = -115mA	P-Ch		4	10	ns
turn-off time	t <sub>off</sub>	V <sub>GS</sub> = 10 to 0 V; V <sub>DD</sub> = 50V; I <sub>D</sub> = 170mA	N-Ch		17	30	ns
		V <sub>GS</sub> = -10 to 0 V; V <sub>DD</sub> = -50V; I <sub>D</sub> = -115mA	P-Ch		25	35	ns